

NEOSEM

Hot and Cold SSD Chamber System

Burn-in Solution for

Production • Qualification • QA • SSD Device Screening

The growing adoption of the new SSD drive technology, Low latency and high densities, are factors that requires from Neosem Technology to continually reinvent its SSD storage test systems in order to stay ahead of industry needs.

SSD manufacturer have an immediate need for a test system that is able to test SSDs as standard generic drives, but to also test for unique SSD drive failure modes and attributes of the underlying solid state technology. Building on its more than two decades history of developing Memory testers, Neosem Technology is introducing a wide array of products designed specifically for SSDs.

Key Features and Options

- Supports SSD Burn-IN and SSD Functional Testing.
- Support various SSD Protocol and Speed
- Comprehensive library of production test scripts, specially designed for SSD drives.
- Easy removal of SSD devices from Test boards
- Damage - proof insertion on Test boards
- Easy to switch from SATA/SAS to PCIe by quick change of Test board
- Supports Neosem DNA2/DNA3 integrated software platform.
- Hot swappable test SSD devices.
- Automatic detection of SSD devices.
- Production Test floor efficiency

Neosem DNA3 Software

- Intuitive script programming for developing test routines.
- Extensive API for user-defined plug-ins.
- Extensive library of test routines.
- Easy to navigate GUI
- User friendly management tools

Applications

- Factory production testing.
- Qualification/Certification.

- QA/Reliability testing.
- SSD Device screening

System Description

SX Series - Architecture

This Neosem SX Series Test system is based on a high density system footprint that can accommodate a minimum of 64 devices (DUTs) up to 256 SSD devices. Industry standard PCIe - bus interfaces are supported. As new generations of interfaces and protocols are defined, Neosem will be ready with upgrade options to keep the system future - proof. This tester supports the robust Neosem 's DNA3 test - software platform with a comprehensive library of standard tests, while allowing user-defined and user-developed test scripts through a provided script development platform. Many options are available to support test needs tailored to customer requirements.

Test Options

- SSD Device Read/Write
- Power margining.
- Current measurement
- Power Cycling
- Controller firmware download
- Full Protocol Functional Testing

Environmental Chamber and Burn-In System

This tester can be delivered as an environmental chamber system, the Neosem Hybrid Chamber, to support low temperature and humidity testing. The capacity, footprint, and power requirements of the Neosem environmental system will vary from those of the Neosem burn-in system.

- Temperature range – 10°C to +85°C
- Ramp rate – 1.5 °C/minute (Without load)
- Four Temperature zone
- Power Cycling
- UART/SMBUS/Serial Communication support
- DUT Temperature monitoring
- Power current measurement

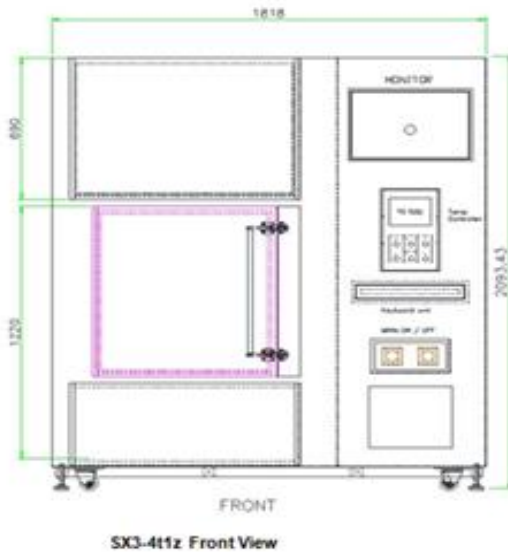
Selected SX3-4t1z Specifications

SX3-4t1z Test System Specifications	
Input voltage	3-phase delta connection 200 ~ 240 VAC
Input current	100 Amps per phase
Input frequency	50Hz (China), 60Hz(USA) , +/- 3Hz
Electrical inlet connector	Screw terminals accepting wires terminated with Jeono JOR 20-10 or equivalent
Circuit breaker protection on chamber	50 Amps per phase
Recommended AC service circuit breaker	50 Amps per phase
Dimensions, Tester, W x D x H	1820 x 1500 x 2100 mm
Dimensions, shipping, W x D x H	2100 x 1800 x 2400 mm
Weight, tester	1100 Kg
Weight, shipping, approximate	1400 Kg

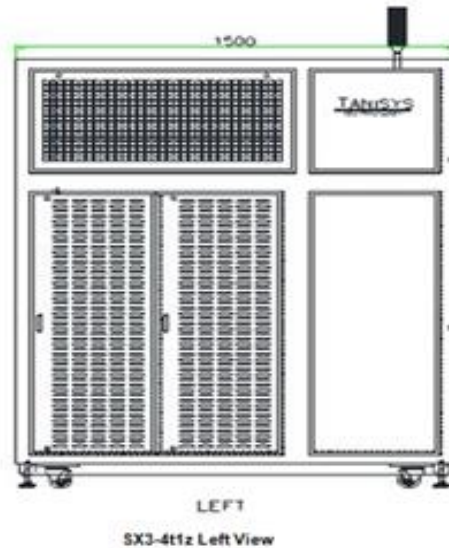
Temperature, operating	20° C to 30° C
Temperature, storage	-10° C to 85° C
Relative humidity, operating	20% to 80%, non-condensing
Exhaust Air	1x Pi 250mm, max 16m/s air (avg 15m/s) (2x3.14x0.125x0.125x15x60 =~88 CMM) by Fan
Inlet Dry air or N2 for cold operation	1x Pi 10mm 3-4 kg/cm2 , from rear bottom
Heat Ramp Up (With and Without Load)	1.5 °C/Min(From 0°C to +80°C (without load) up to 1.5 Kw 2. °C/Min(From- 10°C to +40°C (with load) up to 1.5 Kw
Cool Down Rate (With and Without Load)	2.0 °C/Min(From 0°C to 80°C (without load) 2. °C/Min(From -10°C to +40°C (with load) up to 1.5 Kw

SX3-4t1z System Specifications

System View Front



System View Side



For more information on Neosem product, contact us at : sales@neosemtech.com